## Notice of References Cited

Application/Control No.	Applicant(s)/Pater	nt Under
10/587,117	Reexamination SENDA, AYUMI	
Examiner	Art Unit	
JOHN M. VILLECCO	2622	Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,832,275	12-2004	Aizawa, Takashi	710/62
*	В	US-7,382,398	06-2008	Koyama, Shinichi	348/207.1
*	O	US-7,432,963	10-2008	Chosa, Takashi	348/231.1
*	D	US-6,429,896	08-2002	Aruga et al.	348/231.99
*	Е	US-2006/0244833	11-2006	Abe et al.	348/207.1
*	F	US-2004/0257464	12-2004	Pandit et al.	348/373
*	G	US-2004/0021669	02-2004	Fredlund et al.	345/530
*	н	US-2003/0160890	08-2003	Caspe et al.	348/372
*	-	US-7,119,835	10-2006	Gennetten et al.	348/207.2
*	7	US-7,054,248	05-2006	Wakui, Tetsuya	369/47.36
*	К	US-2002/0051629	05-2002	Endo, Yoshiyuki	386/113
*	L	US-7,177,528	02-2007	Yada et al.	386/111
*	М	US-6,538,692	03-2003	Niwa, Mayumi	348/231.1

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003233957 A	08-2003	Japan	HAMAGUCHI, SHUNEI	
	0	JP 08203192 A	08-1996	Japan	TAGAWA et al.	
	Р	JP 06022259 A	01-1994	Japan	FUJIMOTO, MAKOTO	
	Q					
	R					
	s					
	т					

## NON DATENT DOCUMENTS

NON-PATENT DOCUMENTS		
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	×	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.